

Akaike Information Criterion (AIC)

for model selection in ARMA (p, q):

minimize with respect to p, q

$$AIC(p, q) = -2 \ell(\hat{\phi}_p, \hat{\theta}_q, \hat{\sigma}_\varepsilon^2; X_1^n) + \underbrace{2(p+q)}_{\text{or } 2(p+q+1)} = 2 \cdot (\text{no. of parameters})$$

log-likelihood MLE estimates data

in general, for any reasonable parametric model

$$AIC = -2 \ell(\hat{\beta}_{MLE}; X_1^n) + 2 \dim(\beta)$$

interpretation:

$-2 \ell(\hat{\beta}_{MLE}; X_1^n)$: in-sample goodness of fit measure

✗ as $\dim(\beta)$ increases

$2 \dim(\beta)$: penalty term (for complexity of model)

Reasoning for AIC

• data are realizations of X_1, X_2, \dots, X_n from stochastic process with probability distribution P^*

• class of ARMA(p, q) models:

probability distributions $\{P_{\beta_{p,q}} : \beta_{p,q} = (\phi_p, \theta_q, \sigma_\varepsilon^2) \in A \subset \mathbb{R}^{p+q+2}, p, q \in \mathbb{N}_0\}$

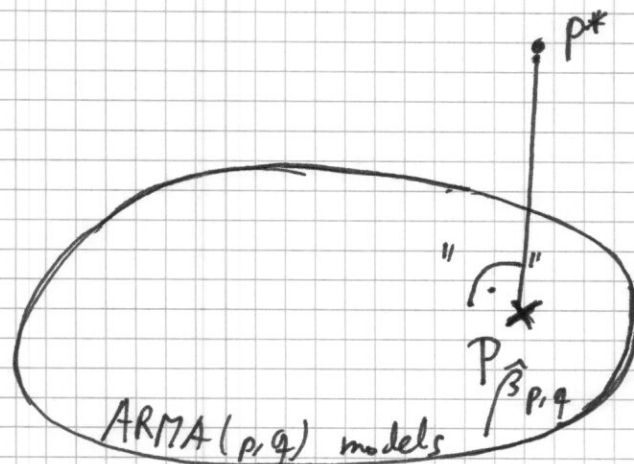
• pseudo-distance between probability distributions:

$$I_n(P, Q) = \int_{\mathbb{R}^n} \log \left(\frac{dP(y_1^n)}{dQ(y_1^n)} \right) dP(y_1^n) \quad \underline{\text{Kullback-Leibler information}}$$

aim: search for model such that

$$I_n(P^*, P_{\hat{\beta}_{p,q}}) \text{ minimal}$$

| MLE in ARMA(p, q)



interpretation:

$$I_n(P^*, P_{\hat{\beta}_{p,q}}) = \int_{\mathbb{R}^n} \log(dP^*(y_1^n)) dP^*(y_1^n) - \int_{\mathbb{R}^n} \log(dP_{\hat{\beta}_{p,q}}(y_1^n)) dP^*(y_1^n)$$

$$= \text{const.} + \mathbb{E}_{y_1^n} \left[-\log(dP_{\hat{\beta}_{p,q}}(y_1^n)) \right]$$

|
w.r.t. model selection

↑
based on
training data X_1, \dots, X_n

where $y_1^n \sim P^*$ is an independent copy of the data to be interpreted as new test data

that is: $\underbrace{\mathbb{E}_{y_1^n} \left[-\log(dP_{\hat{\beta}_{p,q}}(y_1^n)) \right]}_{=T} = \text{expected negative log-likelihood evaluated at test data}$
which is to be minimized

and it holds: AIC is a reasonable estimate of $2T$
(proof is a bit longer...)

\rightsquigarrow AIC(p, q) "small" \iff $I_n(P^*, P_{\hat{\beta}_{p,q}})$ "small"